

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/006,126	SHIEH ET AL.
	Examiner	Art Unit
	Joseph Lauture	2819

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
341	144	3/17/2005	JL
341	136	3/17/2005	JL